## MOSFET - Power, Single

## **N-Channel**

80 V, 50 mΩ, 14 A

### **NVTFS6H888NL**

#### **Features**

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- NVTFS6H888NLWF Wettable Flanks Product
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parar	Symbol	Value	Unit		
Drain-to-Source Voltag	$V_{DSS}$	80	V		
Gate-to-Source Voltage	е		$V_{GS}$	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	14	Α
Current R <sub>θJC</sub> (Notes 1, 2, 3, 4)	Steady	T <sub>C</sub> = 100°C		10	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	23	W
R <sub>θJC</sub> (Notes 1, 2, 3)		T <sub>C</sub> = 100°C		12	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	4.9	Α
Current R <sub>θJA</sub> (Notes 1, 3, 4)	Steady	T <sub>A</sub> = 100°C		3.5	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	2.9	W
R <sub>θJA</sub> (Notes 1, 3)		T <sub>A</sub> = 100°C		1.5	
Pulsed Drain Current	T <sub>A</sub> = 25	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	49	Α
Operating Junction and Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C		
Source Current (Body D	I <sub>S</sub>	20	Α		
Single Pulse Drain-to-S Energy (I <sub>L(pk)</sub> = 0.6 A)	E <sub>AS</sub>	92	mJ		
Lead Temperature for S (1/8" from case for 10 s	TL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 3)	$R_{\theta JC}$	6.4	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	52	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi  $(\Psi)$  is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

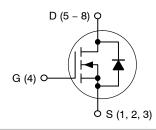


#### ON Semiconductor®

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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
80 V	50 mΩ @ 10 V	44.4	
	67 mΩ @ 4.5 V	14 A	

#### N-Channel





WDFN8 (μ8FL) CASE 511AB







WDFNW8 (Full-Cut µ8FL) CASE 515AN



XXXX = Specific Device Code A = Assembly Location

Y = Year
WW = Work Week

Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Cond	lition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				•	1	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		80			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			10	μА
			T <sub>J</sub> = 125°C			100	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{G}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{E}$	<sub>)</sub> = 15 μA	1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 5 A		41	50	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 5 A		53	67	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 8 V, I <sub>E</sub>	) = 10 A		20		S
CHARGES, CAPACITANCES & GAT	E RESISTANCE				•	•	
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 40 V			258		
Output Capacitance	C <sub>OSS</sub>				36		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				3		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V; I <sub>D</sub> = 10 A			6		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 40 V; I <sub>D</sub> = 10 A			0.7		
Gate-to-Source Charge	Q <sub>GS</sub>				1.2		
Gate-to-Drain Charge	$Q_{GD}$				1.0		1
Plateau Voltage	$V_{GP}$				3.3		V
Total Gate Charge	Q <sub>G(TOT)</sub>				3		nC
SWITCHING CHARACTERISTICS (N					•	1	
Turn-On Delay Time	t <sub>d(ON)</sub>				6		
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V <sub>I</sub>	ne = 64 V.		15		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>	I <sub>D</sub> = 10 A, R <sub>G</sub>	$= 2.5 \Omega$		9		
Fall Time	t <sub>f</sub>				3		1
DRAIN-SOURCE DIODE CHARACT	ERISTICS					•	
Forward Diode Voltage	$V_{SD}$	Voc = 0.V	T <sub>J</sub> = 25°C		0.85	1.2	T
		$V_{GS} = 0 V,$ $I_{S} = 5 A$	T <sub>J</sub> = 125°C		0.73		<b>-</b>
Reverse Recovery Time	t <sub>RR</sub>				23		1
Charge Time	ta	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 10 \text{ A}$			15		ns
Discharge Time	t <sub>b</sub>				7		1
Reverse Recovery Charge	Q <sub>RR</sub>				13		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

6. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

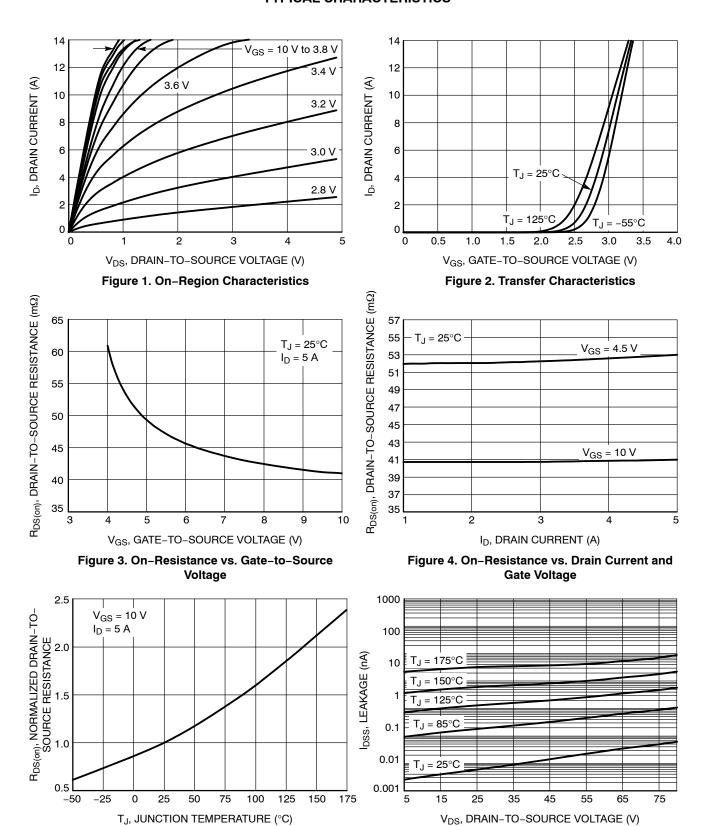
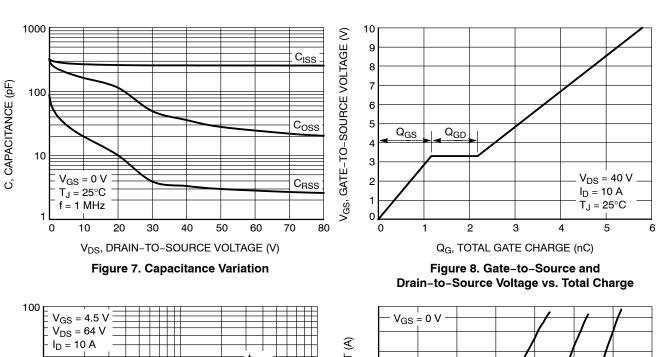


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**



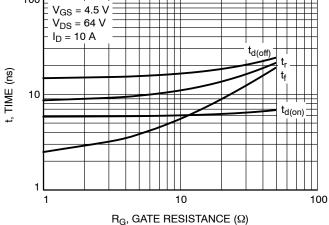


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

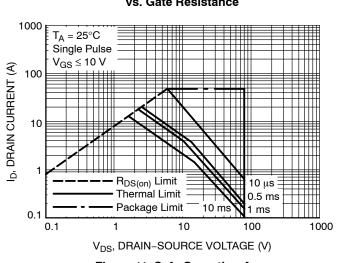


Figure 11. Safe Operating Area

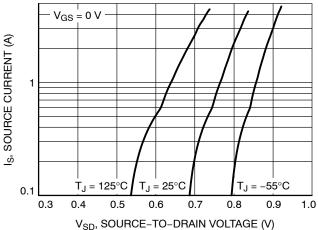


Figure 10. Diode Forward Voltage vs. Current

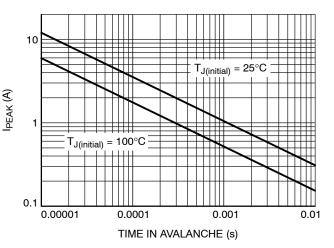


Figure 12. Maximum Drain Current vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

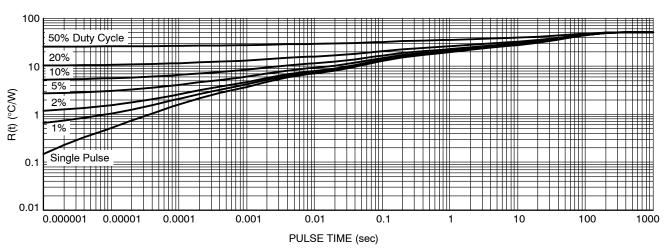


Figure 13. Thermal Response

#### **DEVICE ORDERING INFORMATION**

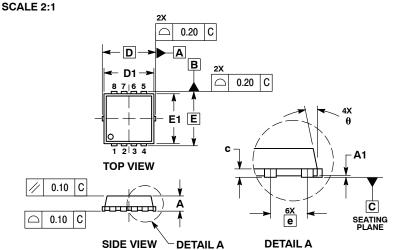
Device	Marking	Package	Shipping <sup>†</sup>
NVTFS6H888NLTAG	888L	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS6H888NLWFTAG	88LW	WDFN8 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



#### WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

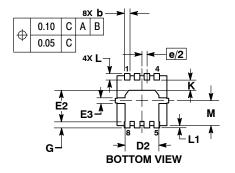
**DATE 23 APR 2012** 



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
  DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
  PROTRUSIONS OR GATE BURRS.

	MILLIMETERS				INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		0	.130 BSC	;	
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC			0.130 BSC		
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е	0.65 BSC			(	0.026 BS	0	
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
М	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	



#### **GENERIC MARKING DIAGRAM\***

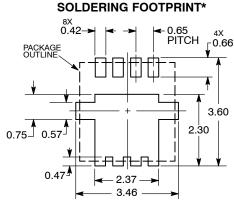


XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.



DIMENSION: MILLIMETERS

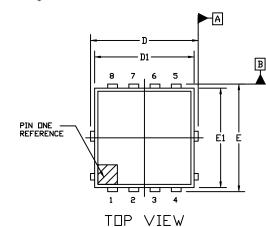
\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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# WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF) CASE 515AN ISSUE O

**DATE 25 AUG 2020** 

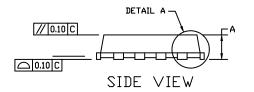


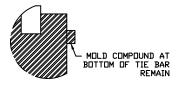


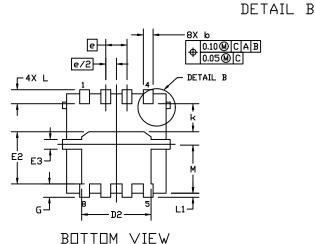
- 1. DIMENSIONING AND TOLERANCING PERASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

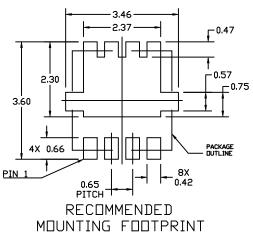
<u> </u>			ATED (	AREA
A1 I	DETAIL	<del>Т</del> А	C SEATIN PLANE	IG

	MILLIMETERS					
DIM	MIN.	NDM.	MAX.			
Α	0.70	0.75	0.80			
A1	0.00		0.05			
b	0.23	0.30	0.40			
c	0.15	0.20	0.25			
D	3.05	3.30	3.55			
D1	2.95	3.05	3.15			
D2	1.98	2.11	2.24			
Ε	3.05	3.30	3.55			
E1	2.95	3.05	3.15			
E2	1.47	1.60	1.73			
E3	0.23	0.30	0.40			
e		0.65 BSC				
G	0.30	0.41	0.51			
K	0.65	0.80	0.95			
L	0.30	0.43	0.59			
L1	0.06	0.13	0.20			
М	1.40	1.50	1.60			









\* For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

## GENERIC MARKING DIAGRAM\*

XXXX AYWW• XXXX = Specific Device Code

A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

(Note: Microdot may be in either location)

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DESCRIPTION:	WDFNW8 3.3x3.3, 0.65P (F	WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF)			

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